

Notice of References Cited	Application/Control No. 10/734,245	Applicant(s)/Patent Under Reexamination NIHEI ET AL.	
	Examiner Christopher P. Schwartz	Art Unit 3683	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,584,397 B2	06-2003	Tanaka et al.	701/70
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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